

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/081,021	SAMN, JONATHAN	
Examiner		Art Unit		Page 1 of 1
Etienne P LeRoux		2161		

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-2004/0078388	04-2004	Melman, Haim Zvi	707/104.1
	C	US-			
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